

In the Claims

1. (currently amended) A magnetic thin film disk comprising:
 - a circumferentially textured AlMg/NiP substrate structure;
 - a layer of CrTi deposited on the substrate;
 - a seed layer of RuAl with a B2 crystallographic structure over the layer of CrTi;
 - an underlayer over the seed layer; and
 - at least one magnetic layer over the underlayer, the magnetic layer having an Mrt orientation ratio greater than one and having a crystallographic orientation with c-axis in-plane for longitudinal recording.
- 2-4 . (cancelled)
5. (original) The magnetic thin film disk of claim 1 wherein the CrTi layer has from 35 to 90 at. % Ti.
6. (original) The magnetic thin film disk of claim 1 wherein the has from 43 to 85 at. % Ti.
7. (currently amended) The magnetic thin film disk of claim [2] 1 wherein the CrTi layer is amorphous or nanocrystalline.
8. (original) The magnetic thin film disk of claim 7 wherein the CrTi is approximately from 10 to 100 nm thick.
9. (currently amended) The magnetic thin film disk of claim [2] 1 wherein the circumferentially textured AlMg/NiP substrate structure has an R_q from 2 to 20 angstroms.
10. (original) The magnetic thin film disk of claim 1 wherein the Mrt orientation ratio is greater than 1.1.

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11-20. (cancelled)

21. (currently amended) A disk drive comprising:

a magnetic transducer including a read and a write head;

a rotatable spindle; and

a magnetic thin film disk mounted on the rotatable spindle allowing magnetic transitions to be written and read on the magnetic thin film disk by the magnetic transducer, the magnetic thin film disk including a circumferentially textured AlMg/NiP substrate structure, including an amorphous or nanocrystalline pre-seed layer of CrTi with 35 to 90 at. % titanium, a seed layer of RuAl with a B2 crystallographic structure on the pre-seed layer of CrTi, at least one underlayer on the seed layer, at least one magnetic layer above the underlayer and the magnetic thin film disk having an Mrt orientation ratio greater than one and having a crystallographic orientation with c-axis in-plane for longitudinal recording.

22. (cancelled)

23. (currently amended) The disk drive of claim 22 wherein the circumferentially textured AlMg/NiP substrate has an R_q from 2 to 20 angstroms.

24-25. (cancelled)